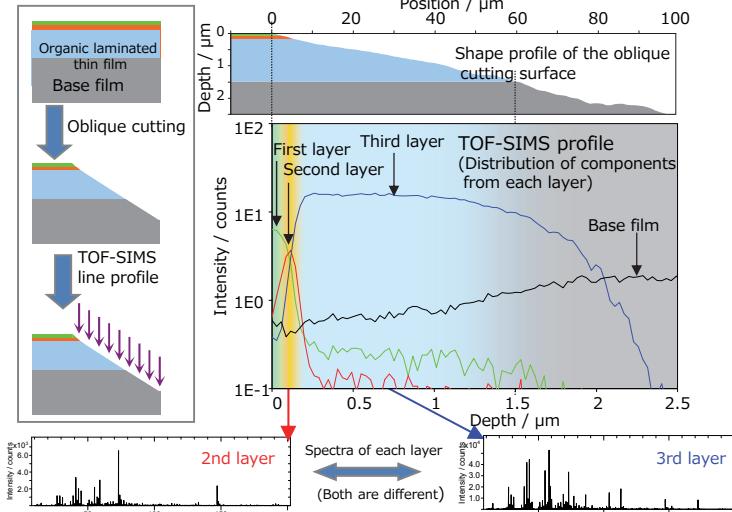


Analysis of liquid crystal impurities and optical films for LCD panels

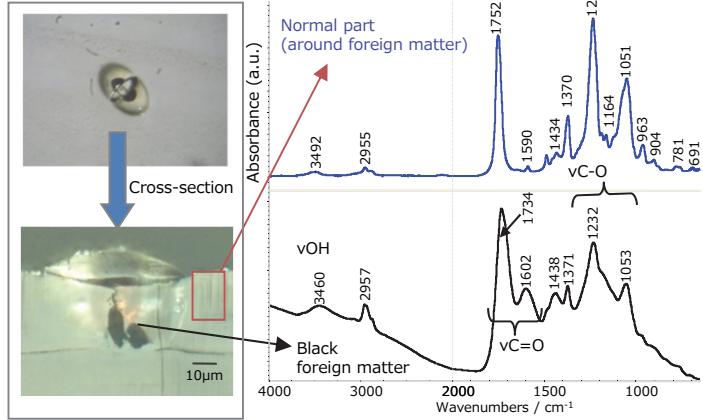
1. Chemical structure of the organic laminated film by precise oblique cutting +TOF-SIMS
2. Qualitative analysis of the foreign substances by microsampling + FT-IR
3. Identifying of the diffusion of sealant components into the liquid crystal in the model testing (HPLC and LC/MS) of LCD manufacturing process

1. Qualitative Analysis of Multilayer Films by Gradient Shaving Preparation + TOF-SIMS Analysis



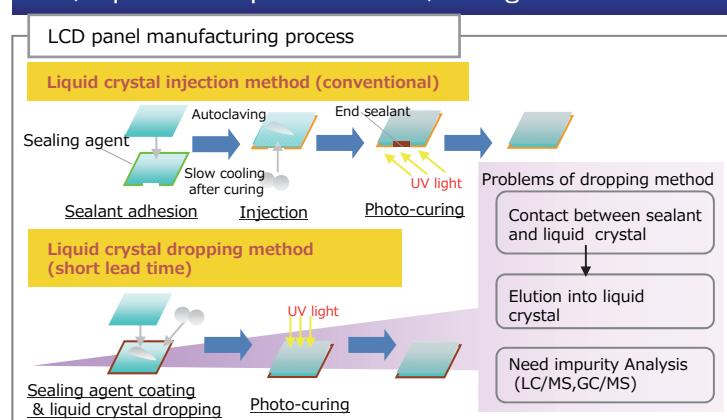
- Precision oblique cutting + TOF-SIMS spectrometry shows three organic laminated thin films (100 nm/100 nm/1.3μm) with TOF-SIMS spectra of each layer.
- Comparing analysis with each layer between samples with different conditions is possible.

2. Analyzing of foreign matters in Multilayer Films by Microsampling + Microscopic FT-IR



- Microsampling + microscopic FT-IR spectrometry on the foreign matter (10μm) shows multiple absorption bands similar to the normal part. OH bond, C=O bond is distinctively strong, and broad spectral shape is different with normal parts.
- The foreign matter is estimated to be derived from heat denaturation of the normal part (film ingredient).

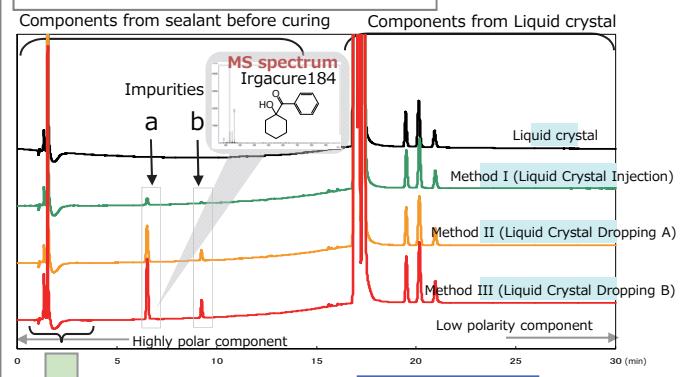
3. Analyses of Liquid Crystal Impurities from Manufacturing Processes (Liquid-to-Liquid Contacts) Using HPLC



After the mockup test of liquid crystal panel manufacturing shows ;

- More impurities were found in the process of higher temperature after sampling of the liquid crystal in liquid-liquid contact and the pre-cure sealant by HPLC and LC/MS
- Succeeded to identify four types of components derived from the sealing agent by Qualitative analysis of the impurity ingredients

HPLC chromatograms of liquid crystal



Model process

